

STL52N25M5

N-channel 250 V, 0.055 Ω, 28 A, PowerFLAT™ (5x6) MDmesh™ V Power MOSFET

Features

Туре	V _{DSS}	R _{DS(on)} max.	I _D ⁽¹⁾
STL52N25M5	250 V	< 0.065 Ω	28 A

- 1. This value is rated according $R_{thj\text{-case.}}$
- Amongst the best R_{DS(on)}* area
- Very low profile package (1 mm max.)
- Excellent switching performance
- High dv/dt capability
- 100% avalanche tested

Application

Switching applications

Description

This device is N-channel MDmesh™ V Power MOSFET based on an innovative proprietary vertical process technology, which is combined with STMicroelectronics' well-known PowerMESH™ horizontal layout structure. The resulting product has extremely low onresistance, which is unmatched among siliconbased Power MOSFETs, making it especially suitable for applications which require superior power density and outstanding efficiency.

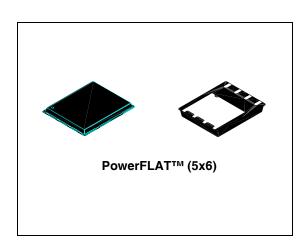


Figure 1. Internal schematic diagram

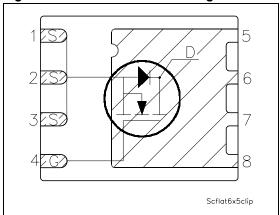


Table 1. Device summary

Order code	Marking	Package	Packaging
STL52N25M5	52N25M5	PowerFLAT™ (5x6)	Tape and reel

September 2010 Doc ID 17819 Rev 1 1/12

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STL52N25M5 Electrical ratings

1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V _{GS}	Gate- source voltage	25	V
I _D ⁽¹⁾	Drain current (continuous) at T _C = 25 °C	28	Α
I _D ⁽¹⁾	Drain current (continuous) at T _C = 100 °C	18	Α
I _{DM} (1),(2)	Drain current (pulsed)	112	Α
I _D ⁽³⁾	Drain current (continuous) at T _C = 25 °C	4.2	Α
I _D ⁽³⁾	Drain current (continuous) at T _C = 100 °C	2.6	Α
I _{DM} (2),(3)	Drain current (pulsed)	16.8	Α
P _{TOT} (1)	Total dissipation at T _C = 25 °C	110	W
P _{TOT} (3)	Total dissipation at T _C = 25 °C	2.5	W
I _{AR}	Avalanche current, repetitive or not-repetitive (pulse width limited by T _J max)	10	Α
E _{AS}	Single pulse avalanche energy (starting $T_J = 25$ °C, $I_D = I_{AR}$, $V_{DD} = 50$ V)	230	mJ
dv/dt ⁽⁴⁾	Peak diode recovery voltage slope	15	V/ns
T _J T _{stg}	Operating junction temperature Storage temperature	- 55 to 150	°C

^{1.} This value is rated according $R_{\mbox{\scriptsize thj-case}}$.

Table 3. Thermal data

Symbol	Parameter	Value	Unit
R _{thj-case}	Thermal resistance junction-case max	1.14	°C/W
R _{thj-a} (1)	Thermal resistance junction-amb max	50	°C/W
T_J	Maximum lead temperature for soldering purpose	300	°C/W

^{1.} When mounted on FR-4 board of 1inch2, 2oz Cu

^{2.} Pulse width limited by safe operating area.

^{3.} This value is rated according R_{thj-a} .

^{4.} $I_{SD} \leq 28 \text{ A}, \text{ di/dt } \leq 400 \text{ A/}\mu\text{s}, V_{Peak} < V_{(BR)DSS}.$

Electrical characteristics STL52N25M5

2 Electrical characteristics

(T_C = 25 $^{\circ}$ C unless otherwise specified).

Table 4. On /off states

Symbol	Parameter	Test conditions		Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	I _D = 1 mA, V _{GS} = 0	250			V
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	V_{DS} = Max rating V_{DS} = Max rating, T_{C} =125 °C			1 100	μ Α μ Α
I _{GSS}	Gate-body leakage current (V _{DS} = 0)	V _{GS} = ± 25 V			100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 100 \mu A$	3	4	5	V
R _{DS(on)}	Static drain-source on- resistance	V _{GS} = 10 V, I _D = 14 A		0.055	0.065	Ω

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	$V_{DS} = 50 \text{ V, f} = 1 \text{ MHz,}$ $V_{GS} = 0$	-	1770 110 17	-	pF pF pF
C _{o(er)} ⁽¹⁾	Equivalent output capacitance energy related	$V_{GS} = 0$, $V_{DS} = 0$ to 80% $V_{(BR)DSS}$	-	93	-	pF
C _{o(tr)} ⁽²⁾	Equivalent output capacitance time related	$V_{GS} = 0$, $V_{DS} = 0$ to 80% $V_{(BR)DSS}$	-	178	-	pF
R _g	Gate input resistance	f=1 MHz open drain	-	2.5	-	Ω
Qg	Total gate charge	V _{DD} = 200 V, I _D = 28 A,		47		nC
Q_{gs}	Gate-source charge	$V_{GS} = 10 \text{ V}$	-	10	-	nC
Q_{gd}	Gate-drain charge	(see Figure 14)		24		nC

^{1.} $C_{o(ef)}$ is a constant capacitance value that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} .

^{2.} $C_{o(tr)}$ is a constant capacitance value that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} .

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max	Unit
t _{d(V)}	Voltage delay time	V _{DD} = 125 V, I _D = 14 A,		40		ns
t _{r(V)}	Voltage rise time	$R_G = 4.7 \Omega, V_{GS} = 10 V$		18		ns
t _{f(i)}	Current fall time	(see Figure 13)	-	64	-	ns
t _{c(off)}	Crossing time	(see Figure 18)		82		ns

Table 7. Source drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max	Unit
I _{SD}	Source-drain current Source-drain current (pulsed)		-		28 112	A A
V _{SD} (2)	Forward on voltage	$I_{SD} = 28 \text{ A}, V_{GS} = 0$	ı		1.6	V
t _{rr}	Reverse recovery time	$I_{SD} = 28 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}$		168		ns
Q_{rr}	Reverse recovery charge	V _{DD} = 60 V, T _J = 25 °C	-	1.2		μC
I _{RRM}	Reverse recovery current	(see Figure 15)		14.5		Α
t _{rr}	Reverse recovery time	I _{SD} = 28 A, di/dt = 100 A/μs		196		ns
Q_{rr}	Reverse recovery charge	V _{DD} = 60 V T _J = 150 °C	-	1.7		μC
I _{RRM}	Reverse recovery current	(see Figure 15)		17		Α

^{1.} Pulse width limited by safe operating area.

^{2.} Pulsed: pulse duration = 300 μ s, duty cycle 1.5%.

Electrical characteristics STL52N25M5

2.1 Electrical characteristics (curves)

Figure 2. Safe operating area

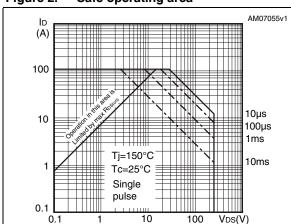


Figure 3. Thermal impedance

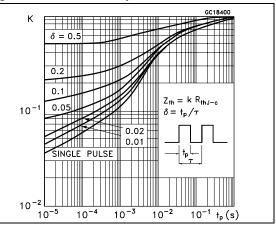


Figure 4. Output characteristics

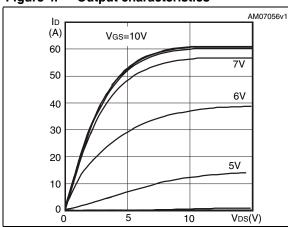


Figure 5. Transfer characteristics

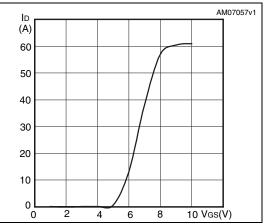
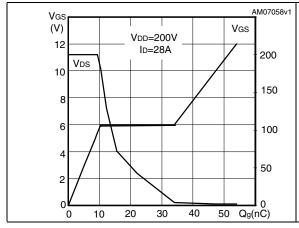


Figure 6. Gate charge vs gate-source voltage Figure 7. Static drain-source on resistance



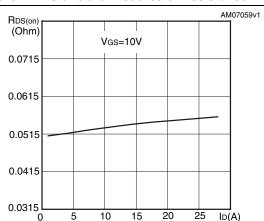
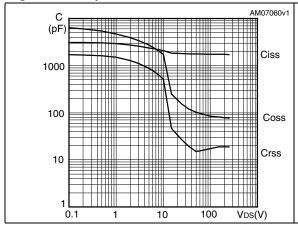


Figure 8. Capacitance variations

Output capacitance stored energy Figure 9.



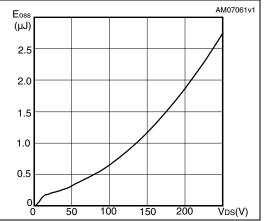
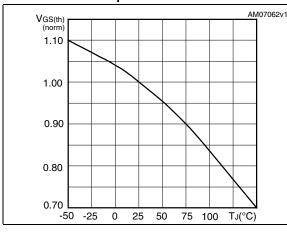


Figure 10. Normalized gate threshold voltage Figure 11. Normalized on resistance vs vs temperature

temperature



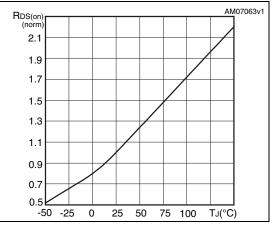
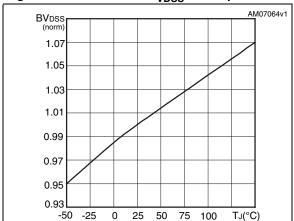


Figure 12. Normalized B_{VDSS} vs temperature



Test circuits STL52N25M5

3 Test circuits

Figure 13. Switching times test circuit for resistive load

Figure 14. Gate charge test circuit

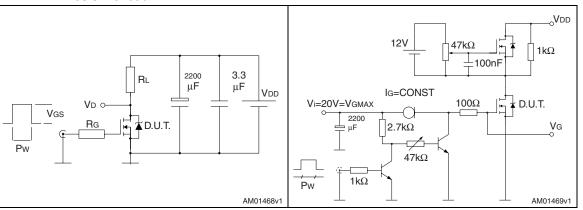


Figure 15. Test circuit for inductive load switching and diode recovery times

Figure 16. Unclamped inductive load test circuit

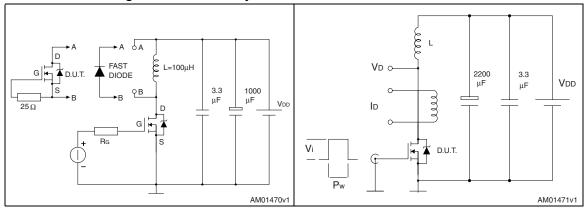
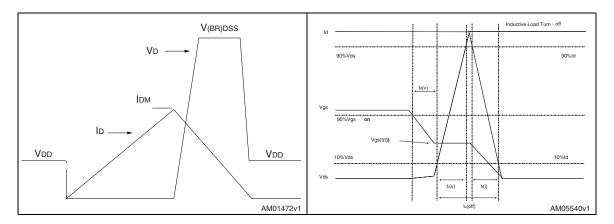


Figure 17. Unclamped inductive waveform

Figure 18. Switching time waveform

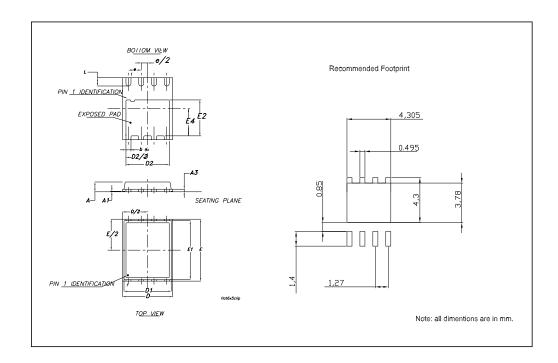


4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK[®] packages, depending on their level of environmental compliance. ECOPACK[®] specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

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DIM.		mm.			inch	
DIIVI.	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
Α	0.80	0.83	0.93	0.031	0.032	0.036
A1		0.02	0.05		0.0007	0.0019
A3		0.20			0.007	
b	0.35	0.40	0.47	0.013	0.015	0.018
D		5.00			0.196	
D1		4.75			0.187	
D2	4.15	4.20	4.25	0.163	0.165	0.167
E		6.00			0.236	
E1		5.75			0.226	
E2	3.43	3.48	3.53	0.135	0.137	0.139
E4	2.58	2.63	2.68		0.103	0.105
е		1.27			0.050	
L	0.70	0.80	0.90	0.027	0.031	0.035



STL52N25M5 Revision history

5 Revision history

Table 8. Document revision history

Date	Revision	Changes
02-Aug-2010	1	First release.

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